

Search Notes

Application/Control No.

10/066,539

Examiner

John J. Tabone, Jr.

Applicant(s)/Patent under
Reexamination

LIEN ET AL.

Art Unit

2117

SEARCHED

Class	Subclass	Date	Examiner
714	725	2/5/2008	JJT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference Search History Printout.		2/5/2008	JJT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
714/724,725,733,736 716/16 395/500.17 (text search only - see search history printout)	11/4/2005	JJT
714/724,725,733,736 716/16 395/500.17 (text search only - see search history printout)	5/10/2006	JJT
714/724,725,733,736 716/16 395/500.17 326/16,38-41 (text search only - see search history printout).	10/11/2006	JJT
IEEE Search (no search history available).	10/11/2006	JJT
714/724,725,733,736 716/16 395/500.17 326/16,38-41 (text search only - see search history printout).	6/29/2007	JJT
Consulted with J. Kerveros concerning Applicants' arguments vs. prior art.	6/29/2007	JJT
714/724,725,733,736 716/16 395/500.17 326/16,38-41 (text search only - see search history printout). UPDATED.	2/5/2008	JJT
Google Search - see search history printout.	2/5/2008	JJT

Search Notes (continued)

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	DATE	EXMR
Assignee and Inventor Search. No Double Patenting found.	2/5/2008	JJT